



Presentation for

Presentation of

CWS – Coherent Wave Scatter System

Robust laser system for process in-line measurements of surface quality parameters in the nanometer range

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Concept

Developers

Product

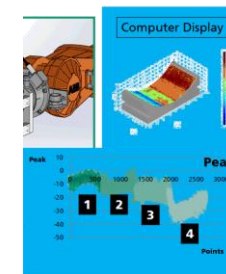
- In-line surface metrology support for automation of laser and robot polishing.



toponova
– kvalitetssäkring av ytor!

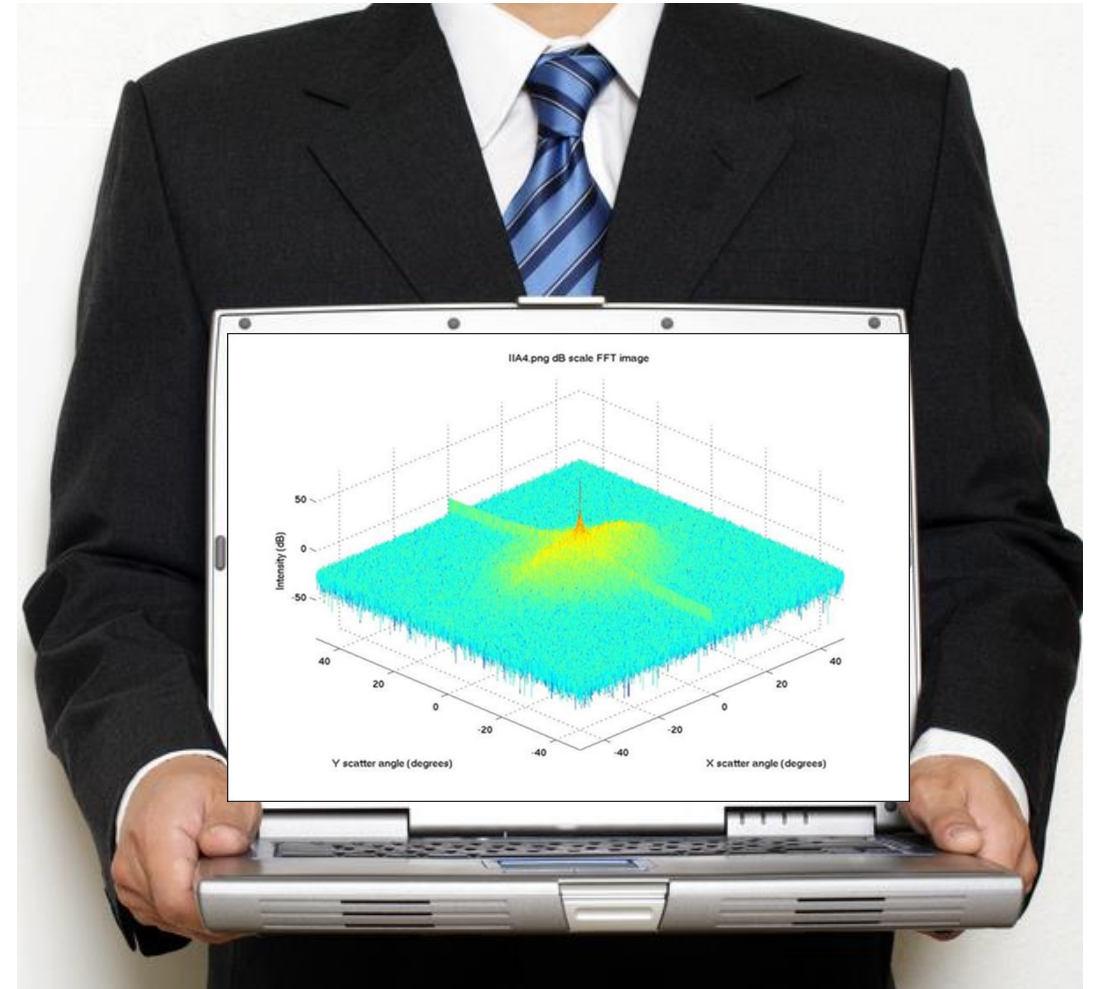
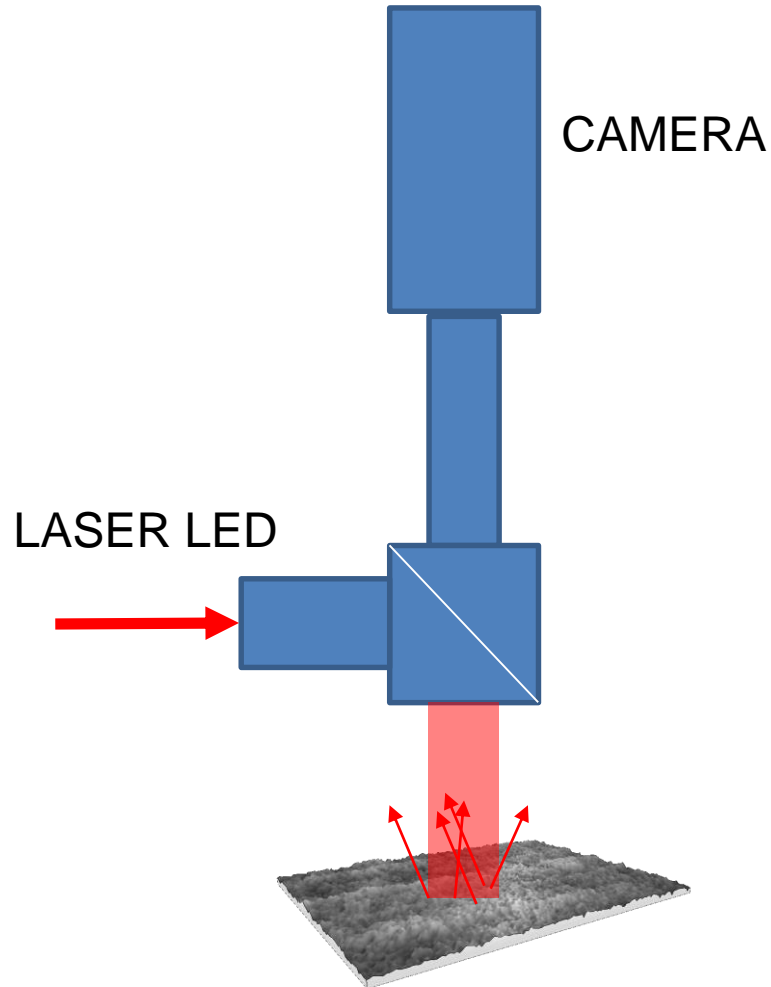


- CWS system from QISAB
- Qualitative statistic measurement system for fast, in-line, process feedback



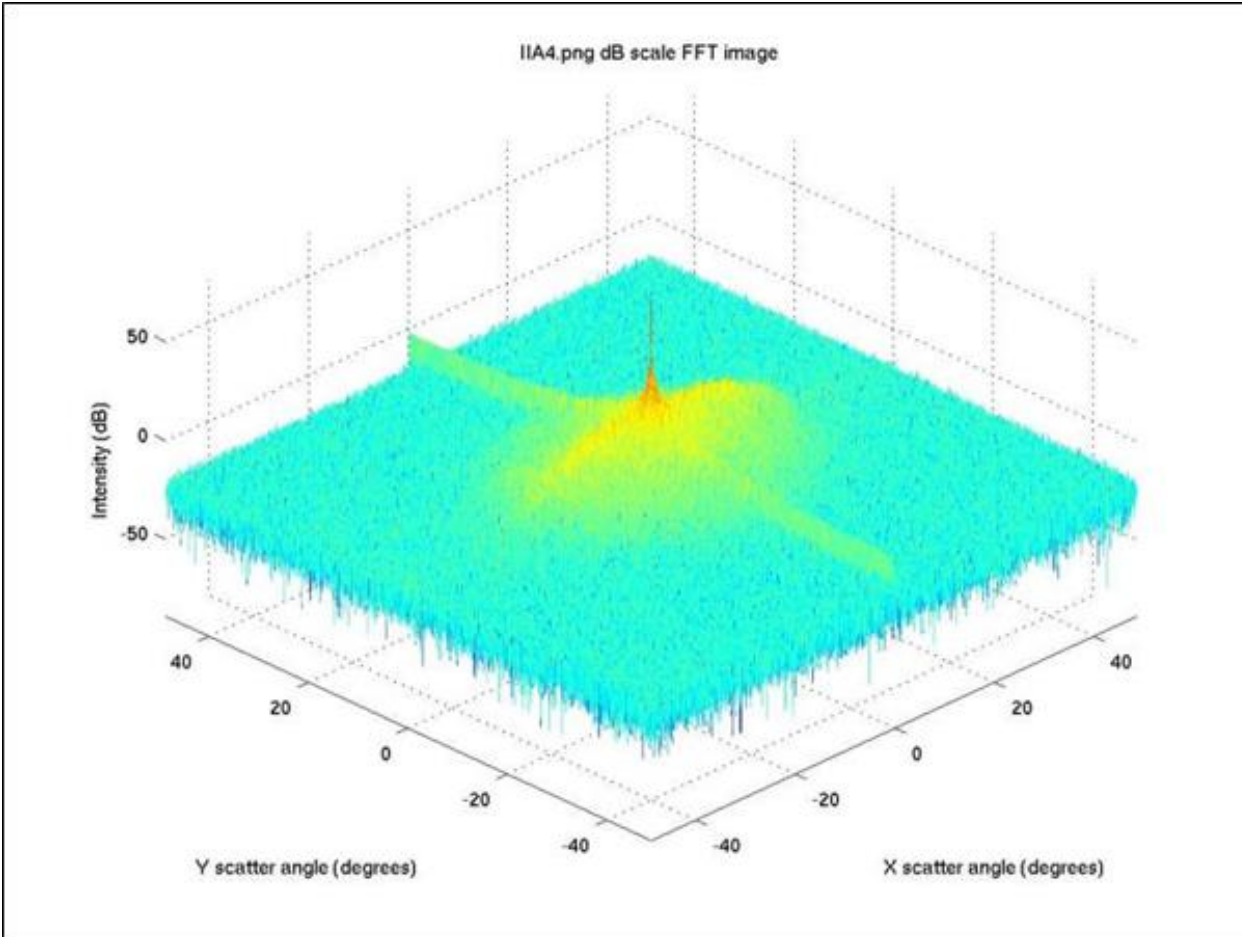
CWS - Coherent Wave Scatter system

Statistical analysis of surface quality in the nm range using laser imaging



CWS surface quality feature parameters

Single shot, 4x4 mm area scatter diagram



Gaussian (dB)

negative value= smoother surface.
Correlates to surface texture amplitude parameter Sq (rms) ISO 25178

Gloss (dB)

Parameter shows how glossy the surface appear.

Texture isotropy

The parameter shows isotropy of the surface and indicates e.g. if polished in one direction. Correlates to surface texture isotropy parameter Str (ISO 25178)

Structure (dB)

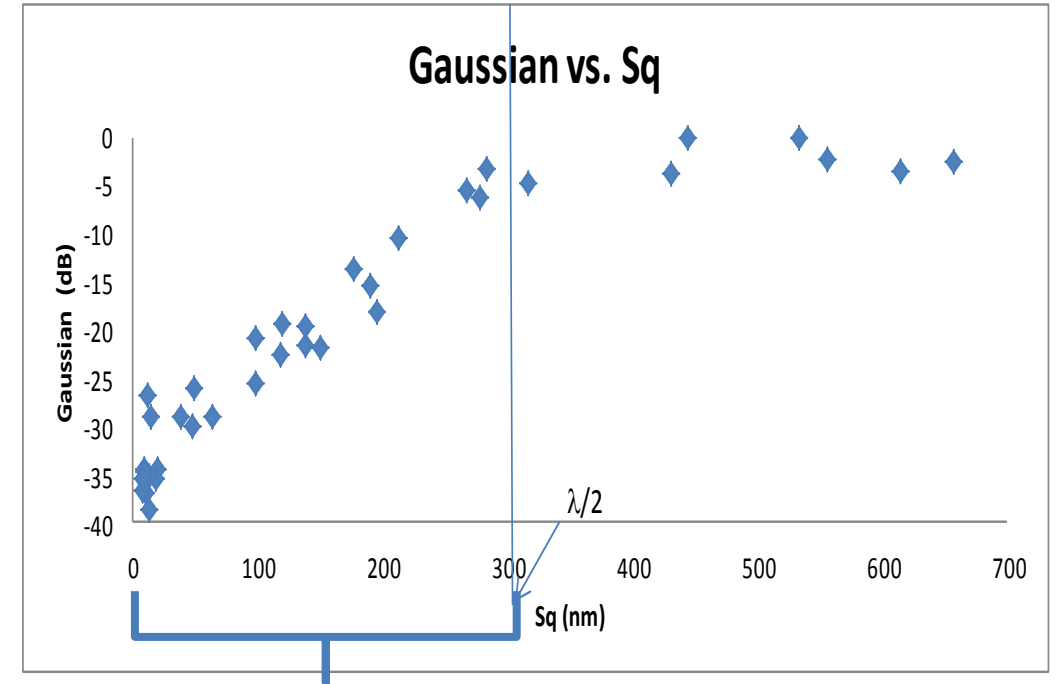
Indicates existence of larger structural features on the surface, like scratches or grooves.

Texture Angle (deg)

This parameter calculates the main angle for the texture of the surface. Correlates to surface texture direction parameter Std (ISO 25178)

Correlation to surface texture

- System used for surfaces, Sq
0,010- 0,350 μm

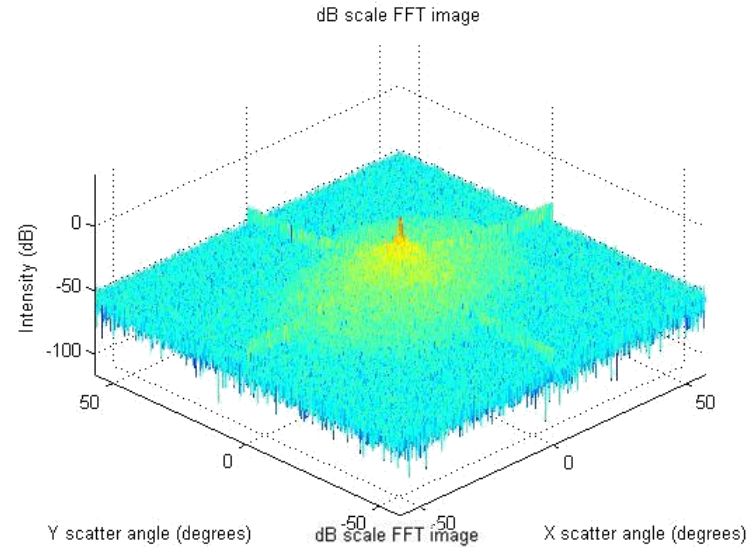
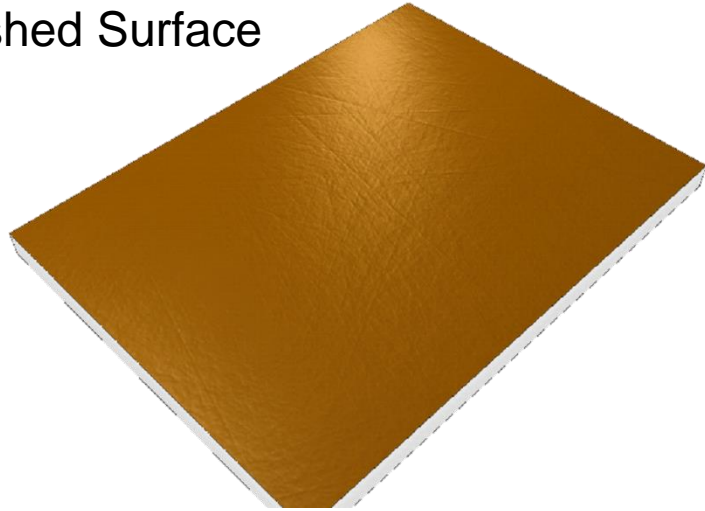


Verified correlation, Gaussian parameter vs. Sq (ISO 25178).

Sq 10 to 350 nm

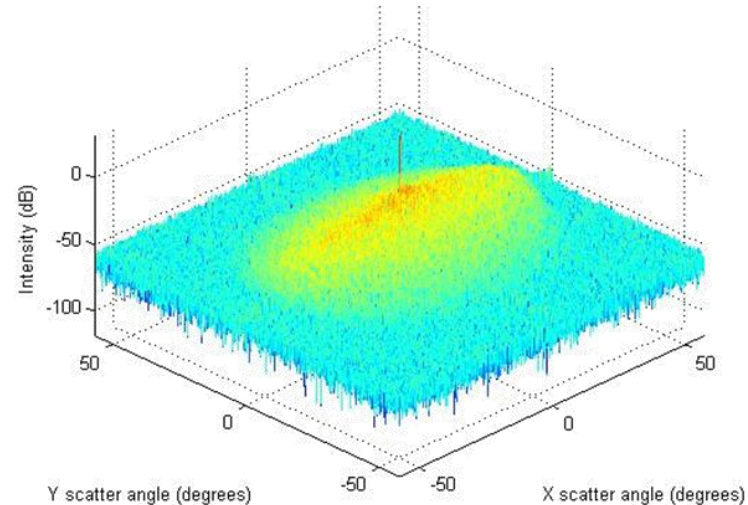
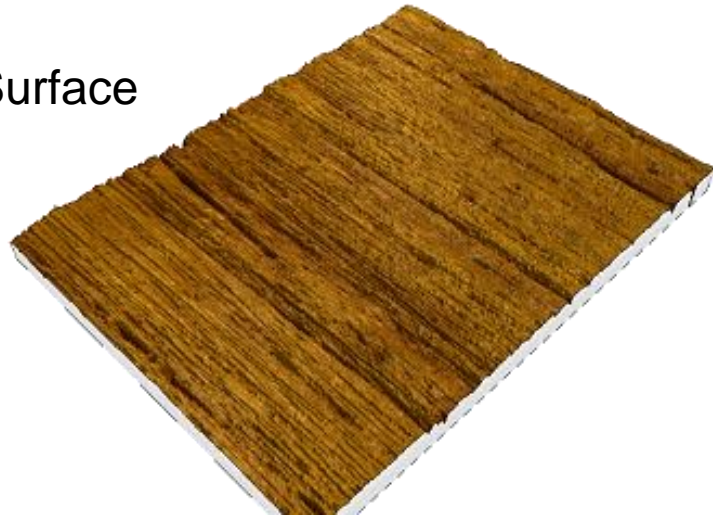
Surface quality by single measurement

High Polished Surface



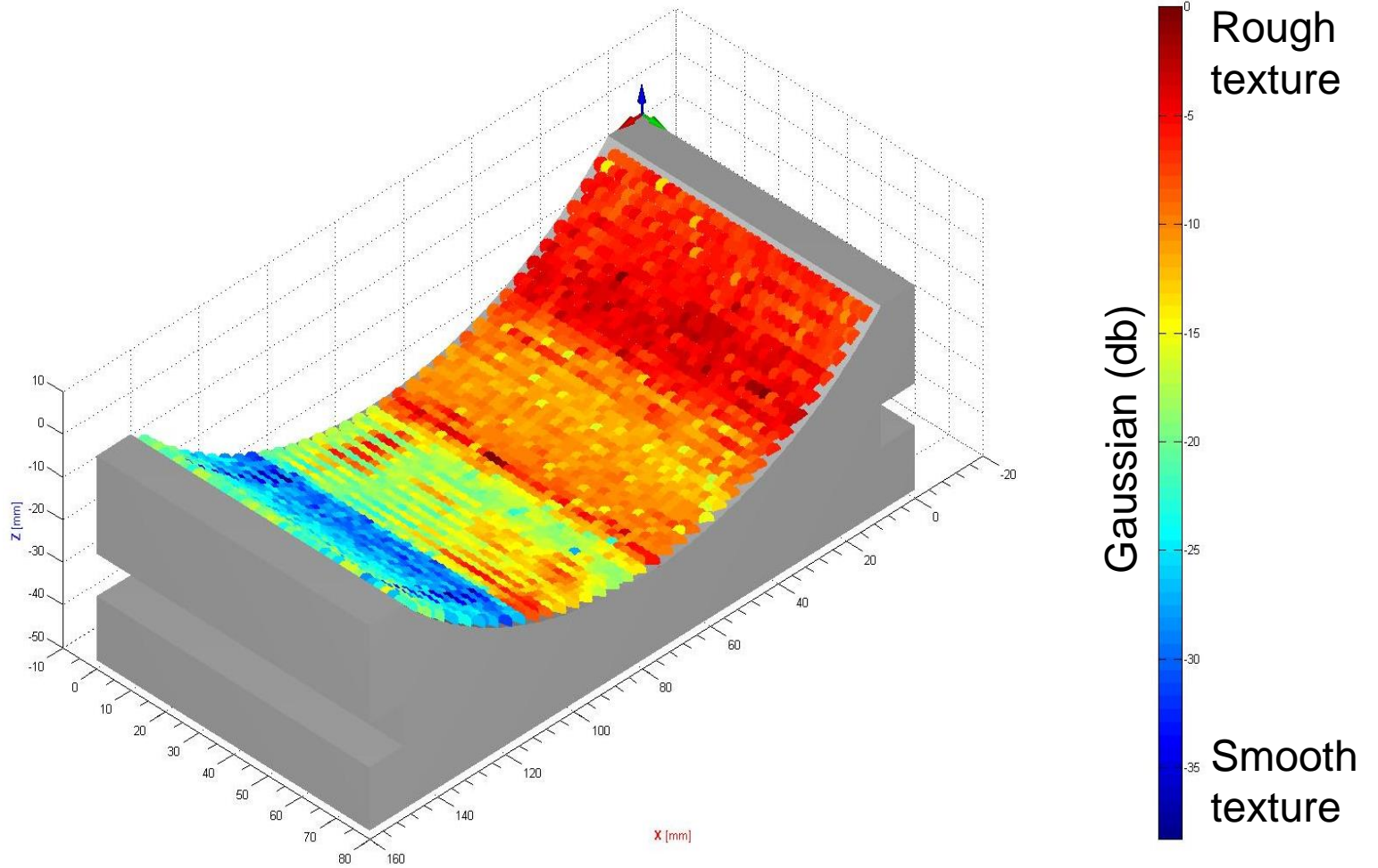
Gaussian:	-24,36 dB
Gloss:	-3,30 dB
Texture isotropy:	0,917
Structure:	-15,24 dB
Texture Angle:	180 deg

Grinded Surface



Gaussian:	0 dB
Gloss:	18,19 dB
Texture isotropy:	0,0048
Structure:	13,99 dB
Texture Angle:	93,21 deg

Surface quality of complete object by scanning



CWS applications and significances

- Suitable for automated in-line processes
- Robust system
- Fast measurement
- Easy determine and follow up of surface quality
- Replaces manual inspections
- Non-contact measurement
- Areal surface measurement
- Independent on surface orientation

Summary: **Wherever objective measurements, control and parameters of surface quality are required**

CWS benefits and added values

- Objective measurements
- Process and quality documentation
- Shorter process time.
- Possibility for process optimizations
- Automating of previous manual process
- In-line surface quality control
- Less scrap by faster detecting quality problems close to production
- Enhanced tool maintenance and replacement scheduling

Summary: Opportunity for significant total cost savings

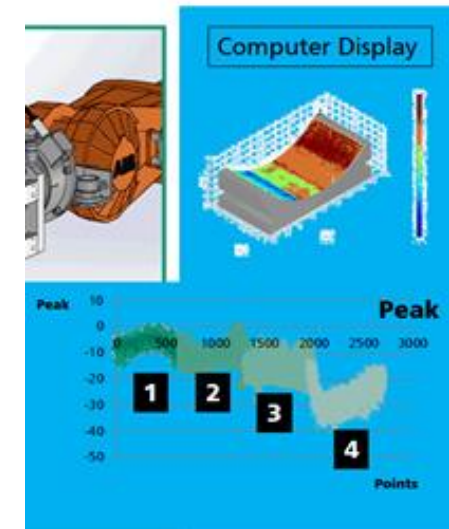
Ex. branches with benefit of CWS

- Mold and Tool Makers
- Automotive Industry
- Aero Industry
- Turbo machinery and Gas Turbines
- Implant Manufacturing, Med-tech



CWS Technical Specification

Laser diode	640 nm @ 0,1 – 10,0 mW
Power requirement	10 W
SW platform	MS Windows
Electrical	110 – 240 VAC
Instrument amplitude resolution	Sq 10 – 350 nm
Depth of field	1 mm
Required positioning acc.	< 1 mm
Measurement area	≥ 4x4 mm
Measuring time	1 ms
Analysis time	0.2-0.5 sec
x, y resolution	2048x2048 pixels
x, y sensitivity	2 – 200 μm
Working distance	75 – 400 mm
Temperature range	-10 – +50°C
Weight sensor	2 kg
Dimensions sensor	300x100x50 mm
Control	Active X
Data output	Active X or to SQL database
Communication	-PC / back-end -Sensor / back-end
	GigE Ethernet, USB, max 1000 m Robot tube: 24 VDC, GigE E., optical fiber, max 100 m



Thank you for your attention!

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